

TGD N-Channel Enhancement Mode Power MOSFET

**Description**

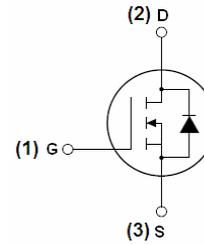
The TGD85H21TC uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in automotive applications and a wide variety of other applications.

**General Features**

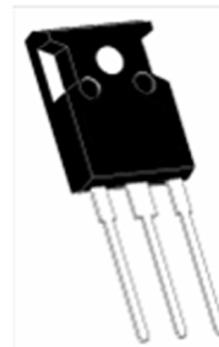
- $V_{DSS} = 85V, I_D = 210A$   
 $R_{DS(ON)} < 4.9m\Omega @ V_{GS} = 10V$
- Good stability and uniformity with high  $E_{AS}$
- Special process technology for high ESD capability
- High density cell design for ultra low  $R_{dson}$
- Fully characterized avalanche voltage and current
- Excellent package for good heat dissipation

**Application**

- Automotive applications
- Hard switched and high frequency circuits
- Uninterruptible power supply



Schematic diagram



TO-247 top view

**100% UIS TESTED!**

**100%  $\Delta V_{ds}$  TESTED!**

**Package Marking and Ordering Information**

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
85H21TC	85H21TC	TO-247	-	-	-

**Absolute Maximum Ratings ( $T_C = 25^\circ C$  unless otherwise noted)**

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	$V_{DSS}$	85	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Drain Current-Continuous	$I_D$	210	A
Drain Current-Continuous( $T_C = 100^\circ C$ )	$I_D (100^\circ C)$	150	A
Pulsed Drain Current	$I_{DM}$	850	A
Maximum Power Dissipation	$P_D$	300	W
Derating factor		2.0	W/ $^\circ C$
Single pulse avalanche energy <sup>(Note 3)</sup>	$E_{AS}$	1800	mJ
Operating Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 To 175	$^\circ C$

**Thermal Characteristic**

Thermal Resistance, Junction-to-Case <sup>(Note 1)</sup>	$R_{\theta JC}$	0.5	$^\circ C/W$
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**Electrical Characteristics (T<sub>C</sub>=25°C unless otherwise noted)**

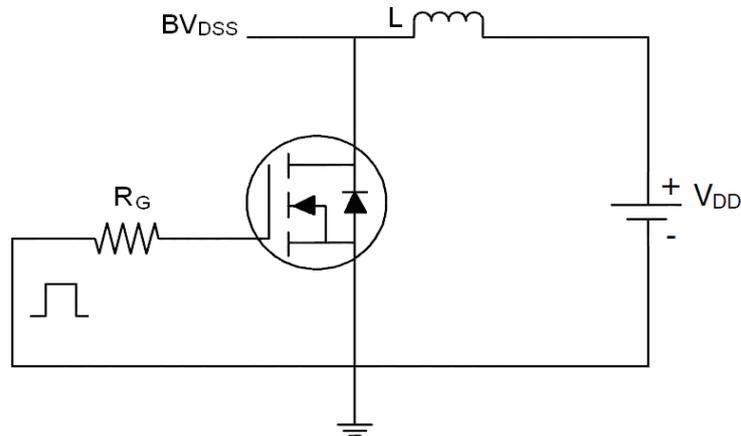
Parameter	Symbol	Condition	Min	Typ	Max	Unit
<b>Off Characteristics</b>						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	85	-	-	V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =85V, V <sub>GS</sub> =0V	-	-	1	μA
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	-	-	±200	nA
<b>On Characteristics</b>						
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	2	3.2	4	V
Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =40A	-	4.0	4.9	mΩ
Forward Transconductance	g <sub>FS</sub>	V <sub>DS</sub> =10V, I <sub>D</sub> =20A	35	-	-	S
<b>Dynamic Characteristics</b>						
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =25V, V <sub>GS</sub> =0V, F=1.0MHz	-	7600	-	PF
Output Capacitance	C <sub>oss</sub>		-	720	-	PF
Reverse Transfer Capacitance	C <sub>rss</sub>		-	346	-	PF
<b>Switching Characteristics</b>						
Turn-on Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> =40V, I <sub>D</sub> =2A, R <sub>L</sub> =15Ω V <sub>GS</sub> =10V, R <sub>G</sub> =2.5Ω	-	23	-	nS
Turn-on Rise Time	t <sub>r</sub>		-	124	-	nS
Turn-Off Delay Time	t <sub>d(off)</sub>		-	84	-	nS
Turn-Off Fall Time	t <sub>f</sub>		-	78	-	nS
Total Gate Charge	Q <sub>g</sub>	I <sub>D</sub> =40A, V <sub>DD</sub> =40V, V <sub>GS</sub> =10V	-	140	-	nC
Gate-Source Charge	Q <sub>gs</sub>		-	40	-	nC
Gate-Drain Charge	Q <sub>gd</sub>		-	57	-	nC
<b>Drain-Source Diode Characteristics</b>						
Diode Forward Voltage	V <sub>SD</sub>	V <sub>GS</sub> =0V, I <sub>S</sub> =40A	-	-	1.2	V
Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25°C, I <sub>F</sub> = 40A di/dt = 100A/μs <sup>(Note2)</sup>	-	110	-	nS
Reverse Recovery Charge	Q <sub>rr</sub>		-	300	-	nC

**Notes:**

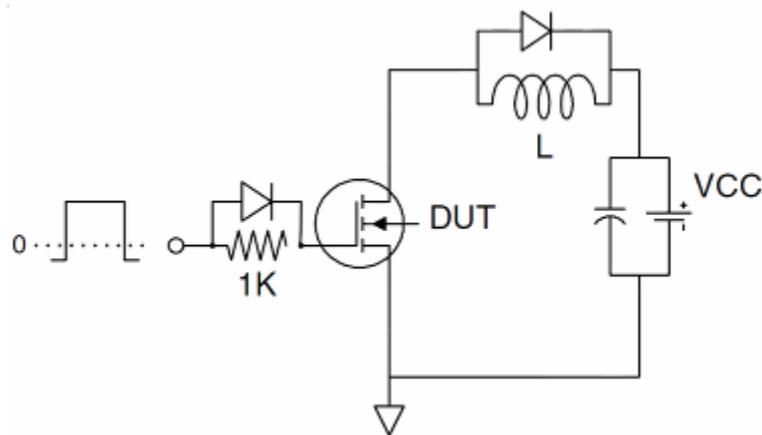
1. Surface Mounted on FR4 Board, t ≤ 10 sec.
2. Pulse Test: Pulse Width ≤ 400μs, Duty Cycle ≤ 2%.
3. EAS condition: T<sub>J</sub>=25°C, V<sub>DD</sub>=42.5V, V<sub>G</sub>=10V, L=2mH, R<sub>G</sub>=25Ω, I<sub>AS</sub>=37A
4. I<sub>SD</sub>≤125A, di/dt≤260A/μs, V<sub>DD</sub>≤V<sub>(BR)DSS</sub>, T<sub>J</sub> ≤175°C

**Test Circuit**

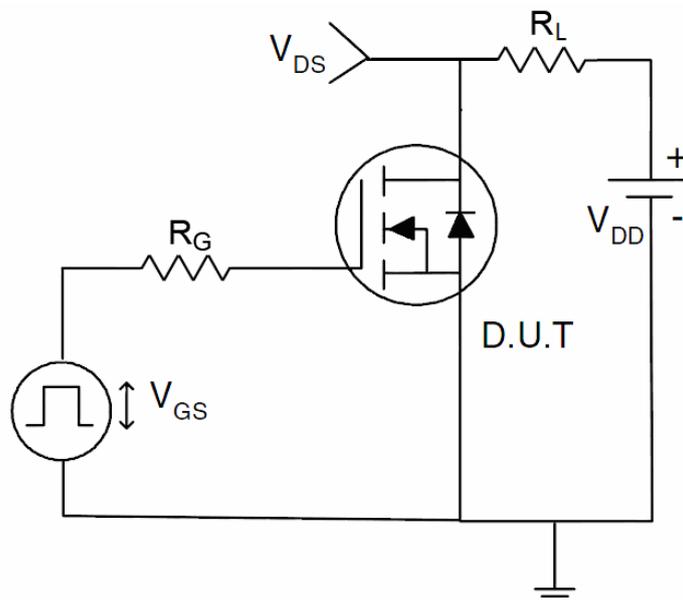
**1)  $E_{AS}$  test Circuit**



**2) Gate charge test Circuit**

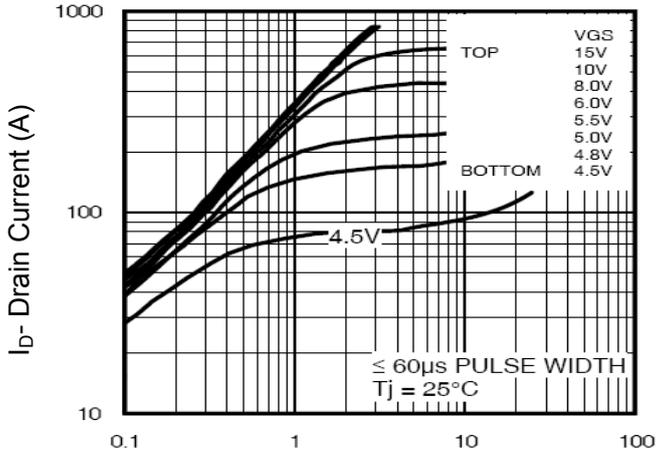


**3) Switch Time Test Circuit**

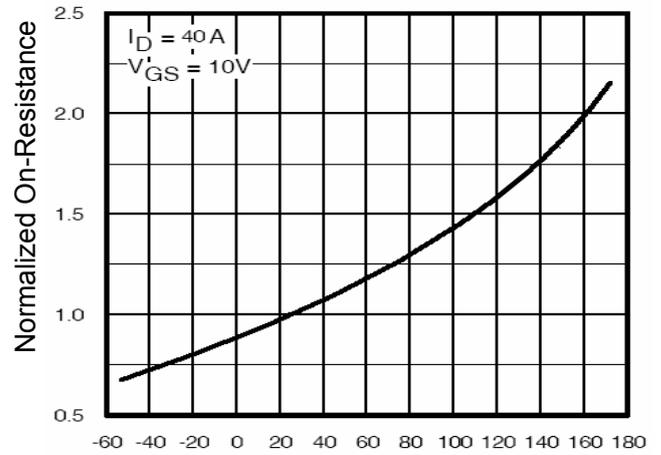




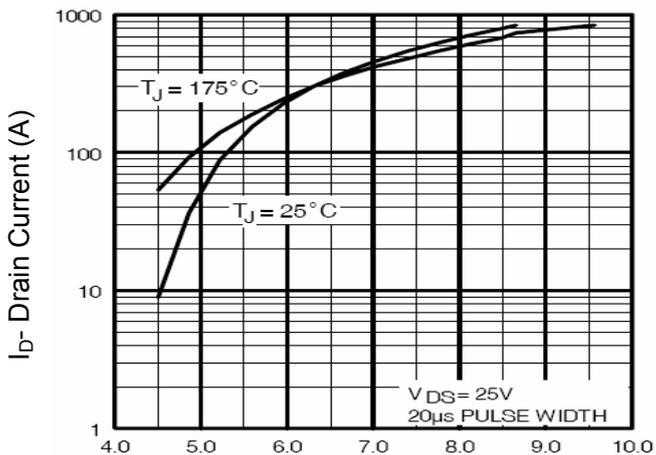
Typical Electrical and Thermal Characteristics



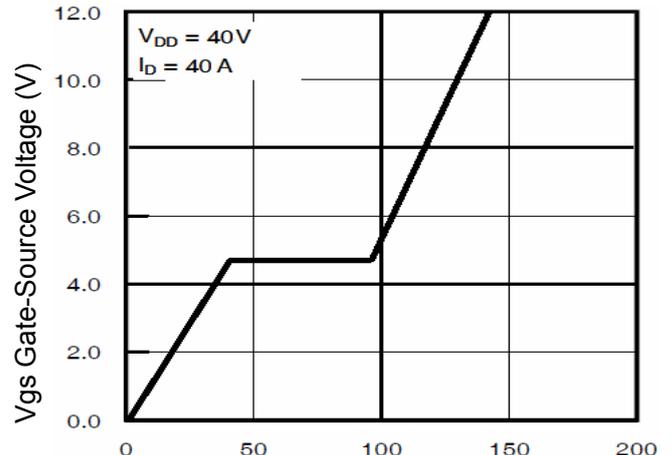
Vds Drain-Source Voltage (V)  
**Figure 1 Output Characteristics**



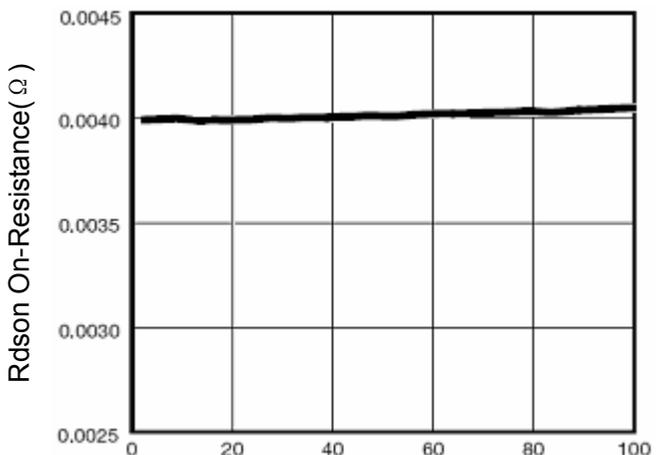
$T_J$ -Junction Temperature( $^\circ C$ )  
**Figure 4 Rdson-Junction Temperature**



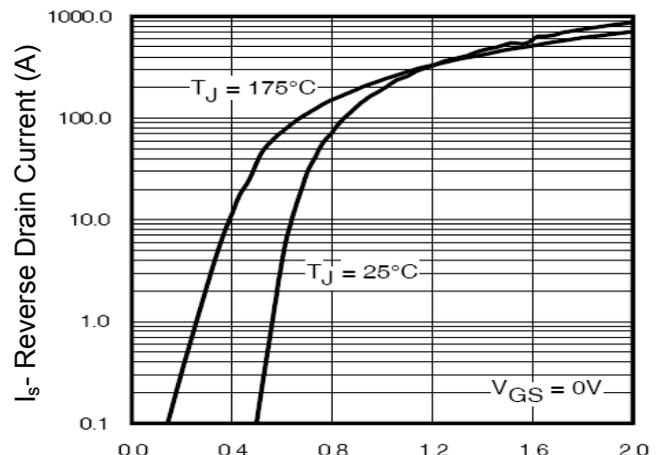
Vgs Gate-Source Voltage (V)  
**Figure 2 Transfer Characteristics**



Qg Gate Charge (nC)  
**Figure 5 Gate Charge**



$I_D$ - Drain Current (A)  
**Figure 3 Rdson- Drain Current**



Vsd Source-Drain Voltage (V)  
**Figure 6 Source- Drain Diode Forward**

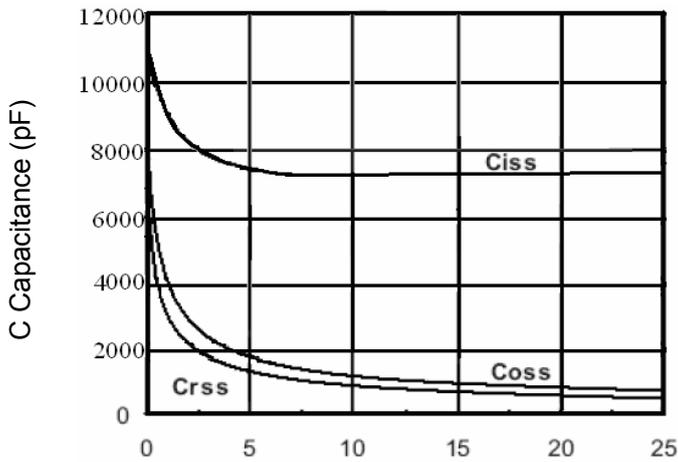


Figure 7 Capacitance vs Vds

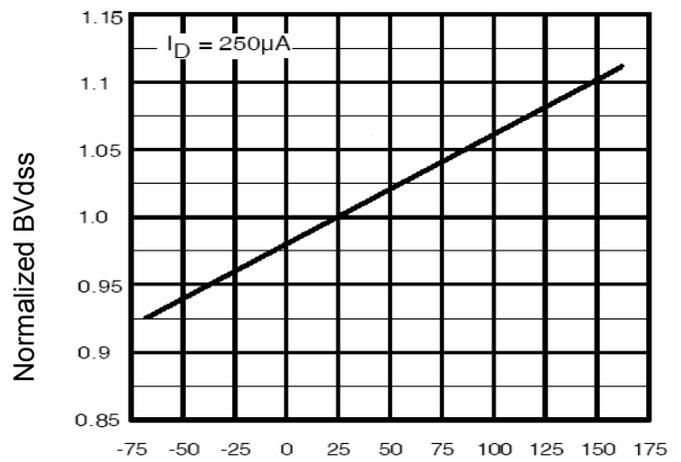


Figure 9  $BV_{DSS}$  vs Junction Temperature

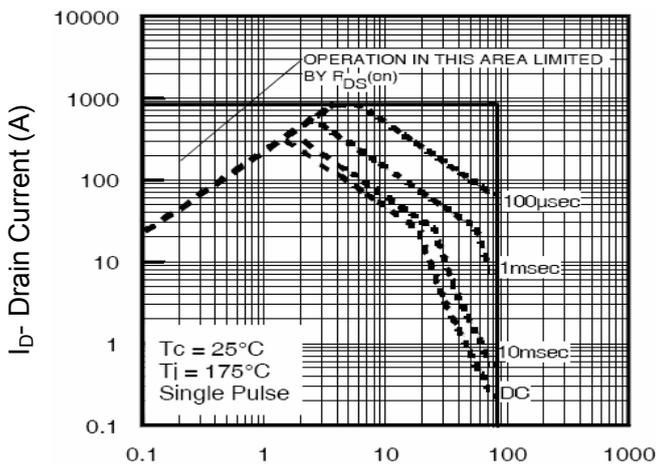


Figure 8 Safe Operation Area

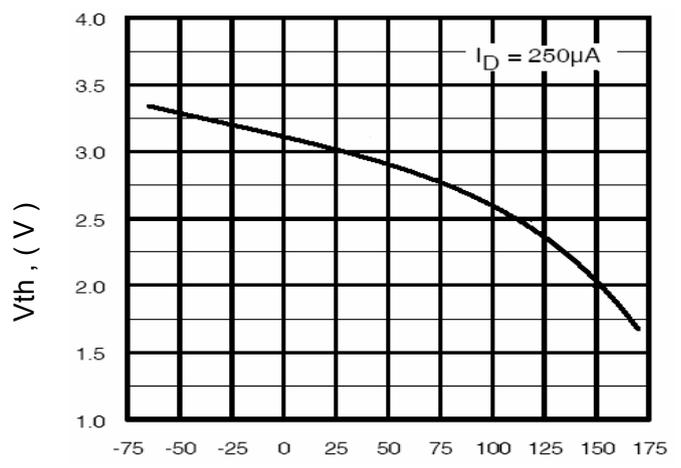


Figure 10  $V_{GS(th)}$  vs Junction Temperature

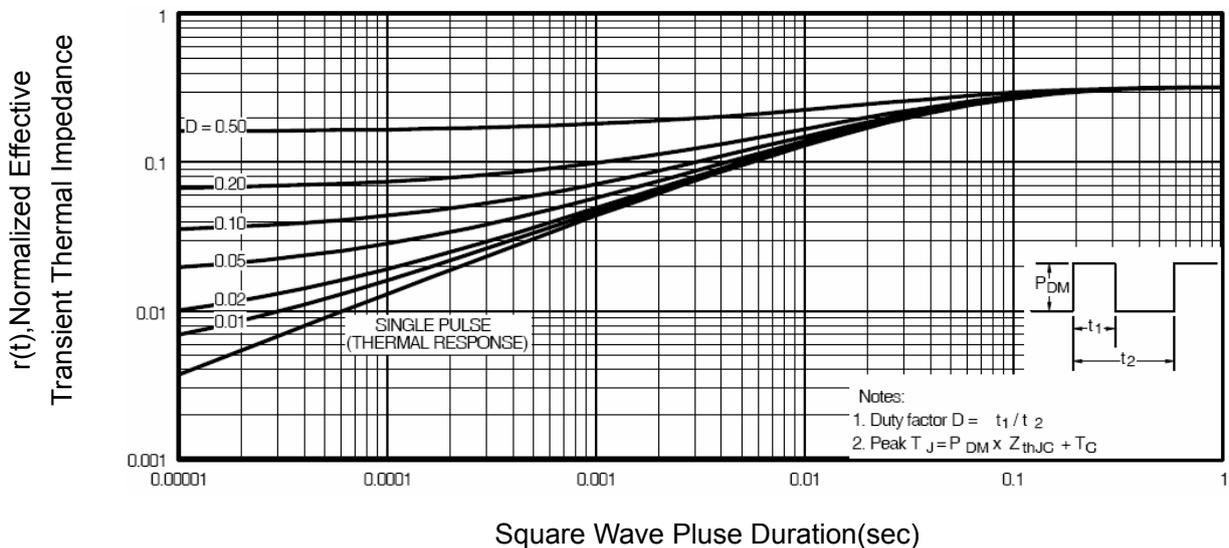
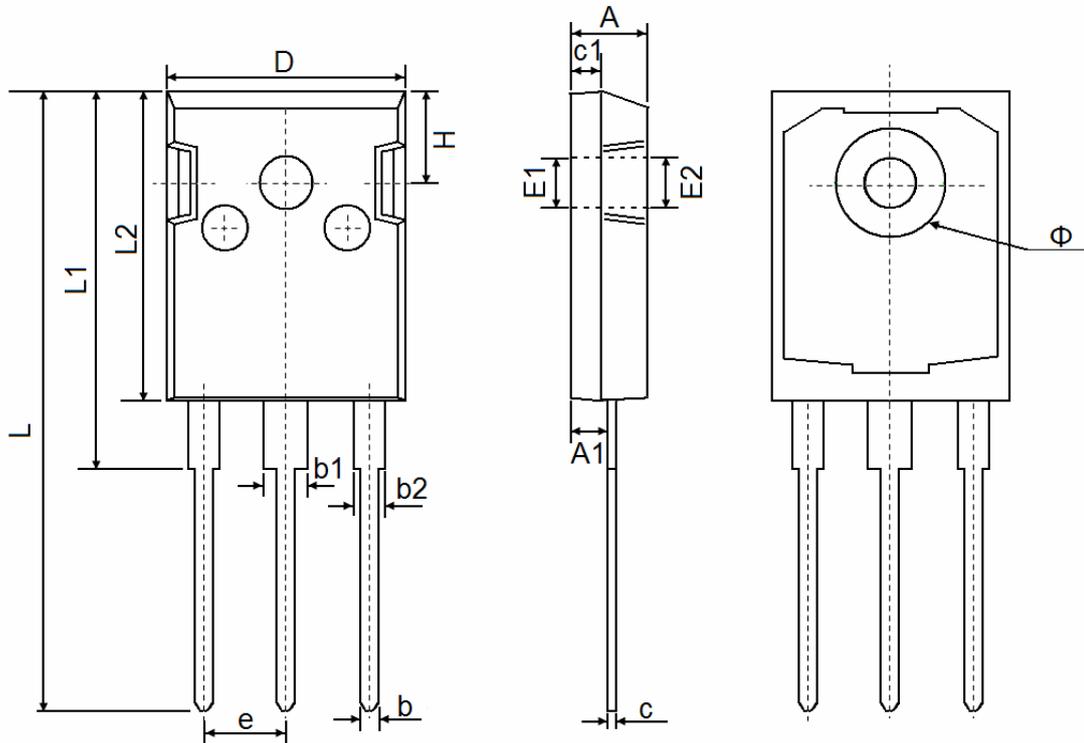


Figure 11 Normalized Maximum Transient Thermal Impedance



TO-247 Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	4.850	5.150	0.191	0.200
A1	2.200	2.600	0.087	0.102
b	1.000	1.400	0.039	0.055
b1	2.800	3.200	0.110	0.126
b2	1.800	2.200	0.071	0.087
c	0.500	0.700	0.020	0.028
c1	1.900	2.100	0.075	0.083
D	15.450	15.750	0.608	0.620
E1	3.500 REF		0.138 REF	
E2	3.600 REF		0.142 REF	
L	40.900	41.300	1.610	1.626
L1	24.800	25.100	0.976	0.988
L2	20.300	20.600	0.799	0.811
Φ	7.100	7.300	0.280	0.287
e	5.450 TYP		0.215 TYP	
H	5.980 REF		0.235 REF	